# **Power MOSFET**

# –60 V, 16 m $\Omega$ , –61 A, Single P–Channel

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- High Current Capability
- Avalanche Energy Specified
- AEC-Q101 Qualified
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	-60	V
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain Cur-		T <sub>C</sub> = 25°C	I <sub>D</sub>	-61	Α
rent R <sub>θJC</sub> (Note 1)	Steady	T <sub>C</sub> = 100°C		-43	
Power Dissipation R <sub>θJC</sub>	State	T <sub>C</sub> = 25°C	$P_{D}$	118	W
(Note 1)		T <sub>C</sub> = 100°C		59	
Continuous Drain Cur-		T <sub>A</sub> = 25°C	I <sub>D</sub>	-11	Α
rent R <sub>θJA</sub> (Notes 1 & 2)	Steady	T <sub>A</sub> = 100°C		-8	
Power Dissipation R <sub>θJA</sub>	State	T <sub>A</sub> = 25°C	$P_{D}$	4.1	W
(Notes 1 & 2)		T <sub>A</sub> = 100°C		2.1	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	-419	Α
Current Limited by Package (Note 3)	T <sub>A</sub> = 25°C		I <sub>Dmaxpkg</sub>	60	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Source Current (Body Diode)			I <sub>S</sub>	-118	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, V <sub>DD</sub> = 50 V, V <sub>GS</sub> = 10 V, $I_{L(pk)}$ = 40 A, L = 0.3 mH, $R_G$ = 25 $\Omega$ )			E <sub>AS</sub>	240	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain)	$R_{\theta JC}$	1.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	37	

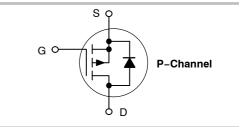
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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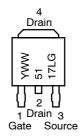
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	
-60 V	16 mΩ @ –10 V	-61 A	
-60 V	22 mΩ @ -4.5 V	-01 A	





DPAK CASE 369C STYLE 2

# MARKING DIAGRAMS & PIN ASSIGNMENT



Y = Year

WW = Work Week

5117L = Device Code

G = Pb-Free Package

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NVD5117PLT4G	DPAK (Pb-Free)	2500 / Tape & Reel

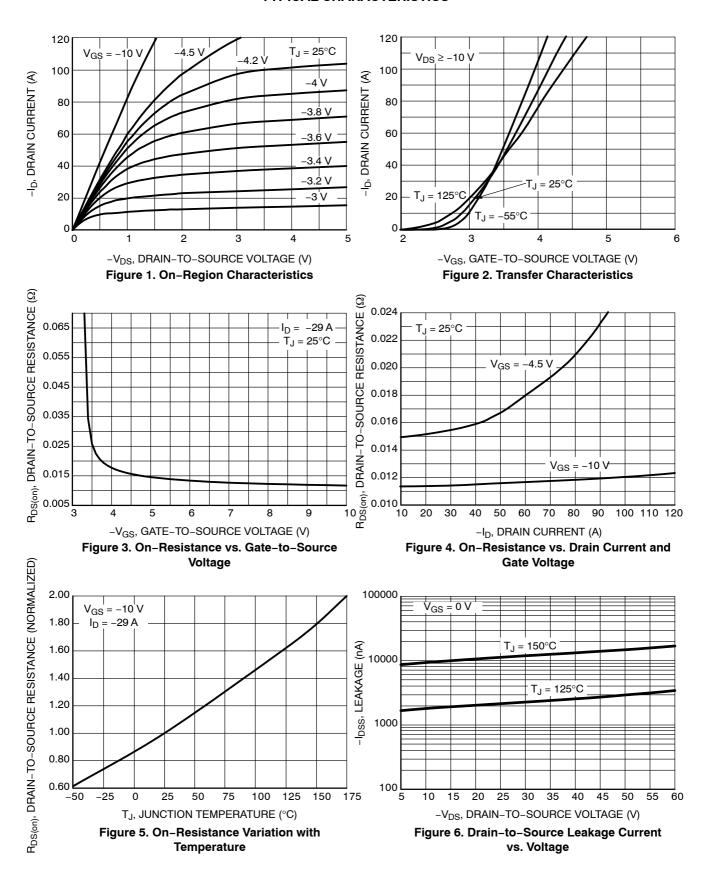
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu A$		-60			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = -60 \text{ V}$ $T_{J} = 25^{\circ}\text{C}$				-1.0	μΑ
		$V_{DS} = -60 \text{ V}$	T <sub>J</sub> = 125°C			-100	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	S = ±20 V			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= -250 μΑ	-1.5		-2.5	V
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = −10 V, I	<sub>D</sub> = -29 A		12	16	mΩ
		$V_{GS} = -4.5 \text{ V},$	I <sub>D</sub> = -29 A		16	22	1
Froward Transconductance	9FS	V <sub>DS</sub> = −15 V, I	<sub>D</sub> = -15 A		30		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, f =	1.0 MHz,		4800		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -2$	25 V		480		1
Reverse Transfer Capacitance	C <sub>rss</sub>				320		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>DS</sub> = -48 V,	$V_{GS} = -48 \text{ V}.$ $V_{GS} = -4.5 \text{ V}$ 49	49		nC	
		$I_{\rm D} = -29  {\rm A}^{2}$	V <sub>GS</sub> = -10 V		85		1
Threshold Gate Charge	Q <sub>G(TH)</sub>		•		3		1
Gate-to-Source Charge	$Q_{GS}$	V <sub>GS</sub> = -4.5 V, V	ns = -48 V,		13		1
Gate-to-Drain Charge	$Q_{GD}$	$V_{GS} = -4.5 \text{ V}, V_{DS} = -48 \text{ V},$ $I_{D} = -29 \text{ A}$			28		1
Plateau Voltage	$V_{GP}$				3.2		V
SWITCHING CHARACTERISTICS (No	otes 4)						
Turn-On Delay Time	t <sub>d(on)</sub>				22		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = -4.5 V, V	ns = -48 V,		195		1
Turn-Off Delay Time	t <sub>d(off)</sub>	I <sub>D</sub> = -29 A, R			50		1
Fall Time	t <sub>f</sub>				132		1
DRAIN-SOURCE DIODE CHARACTE	RISTICS					•	•
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 \text{ V},$ $I_{S} = -29 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$			-0.86	-1.0	٧
					-0.74		1
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS}$ = 0 V, $dI_s/dt$ = 100 A/ $\mu$ s, $I_s$ = -29 A			36		ns
Charge Time	ta				19		1
Discharge Time	t <sub>b</sub>				17		1
Reverse Recovery Charge	Q <sub>RR</sub>				44		nC

<sup>4.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu s,$  Duty Cycle  $\leq$  2%.

#### TYPICAL CHARACTERISTICS



#### **TYPICAL CHARACTERISTICS**

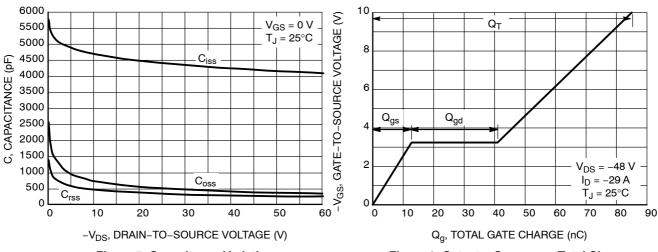


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source vs. Total Charge

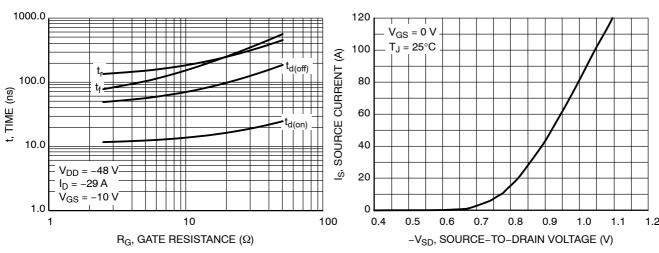


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

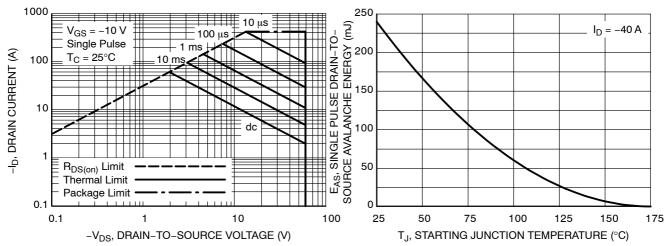


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

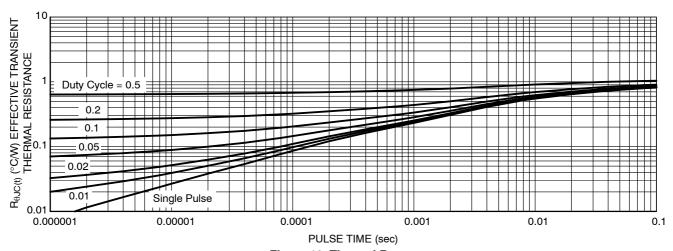
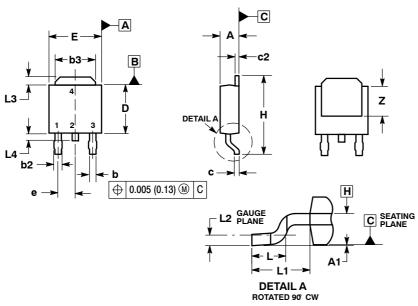


Figure 13. Thermal Response

## **PACKAGE DIMENSIONS**

### **DPAK (SINGLE GAUGE)**

CASE 369C-01 ISSUE D



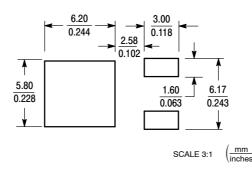
#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M. 1994.
- 2. CONTROLLING DIMENSION: INCHES.
- 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- MENSIONS DS, LS BIOLZ.

  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
<b>A</b> 1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
C	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	0.108 REF		REF	
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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